

Search Notes



Application/Control No.

10/682,015

Examiner

James Phan

Applicant(s)/Patent under Reexamination

DEWA ET AL.

Art Unit

2872

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
| 359 | 198 | 5/05 | J.P. |
| | 199 | | |
| | 223- | | |
| | 226 | | |
| 310 | 36,40R | | |
| | 40MM | | |
| | 152 | | |
| | 311 | | |
| 335 | 229 | | |
| | 302 | | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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| All above | | 5/05 | J.P. |

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|-----------------------|------|------|
| EAST. See attachments | 5/05 | J.P. |
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